



# RADIO TEST REPORT

Test Report No. : 30KE0260-HO-02-A-R1


Applicant : Canon Inc.  
Type of Equipment : Wireless Microphone  
Model No. : DV840210  
FCC ID : AZD210  
Test regulation : FCC Part 15 Subpart C: 2010  
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This report is a revised version of 30KE0260-HO-02-A. 30KE0260-HO-02-A is replaced with this report.


Date of test:

October 28 and 29, 2010

Representative  
test engineer:

  
Tomotaka Sasagawa  
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Approved by:

  
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Manager of EMC Service



NVLAP LAB CODE: 200572-0

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## **SECTION 1: Customer information**

Company Name	:	Canon Inc.
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Contact Person	:	Takato Matsuura

## **SECTION 2: Equipment under test (E.U.T.)**

### **2.1 Identification of E.U.T.**

Type of Equipment	:	Wireless Microphone
Model No.	:	DV840210
Serial No.	:	Refer to Section 4, Clause 4.2
Rating	:	DC 0.95 - 1.8V
Receipt Date of Sample	:	October 28, 2010
Country of Mass-production	:	Japan
Condition of EUT	:	Engineering prototype (Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT	:	No Modification by the test lab

### **2.2 Product description**

Model No: DV840210 (referred to as the EUT in this report) is the Wireless Microphone.

#### **General Specification**

Clock frequency(ies) in the system	:	32MHz
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#### **Radio Specification**

##### **[Bluetooth (Ver. 2.0 without EDR function)]**

(Transmitting part)

Radio Type	:	Transceiver
Frequency of Operation	:	2402 - 2480MHz
Modulation	:	FHSS
Antenna type	:	Chip Antenna (EBMGH8A)
Antenna Gain	:	+0.5dBi
Method of Frequency Generation	:	Crystal
Operating voltage (inner)	:	DC 3.0 - 3.6V
Operating temperature range	:	0 - +40 deg. C

(Receiving part)

Type of Receiver	:	Direct conversion
Antenna Type	:	Chip Antenna (EBMGH8A)
Method of Frequency Generation	:	Crystal
Operating voltage (inner)	:	DC 3.0 - 3.6V
Operating temperature range	:	0 - +40 deg. C

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## SECTION 3: Test specification, procedures & results

### 3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2010, final revised on October 13, 2010

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators  
Section 15.207 Conducted limits  
Section 15.247 Operation within the bands 902-928MHz,  
2400-2483.5MHz, and 5725-5850MHz

\* The EUT complies with FCC Part 15 Subpart B: 2010, final revised on October 13, 2010

### 3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.2	FCC: Section 15.207 IC: RSS-Gen 7.2.2	N/A	N/A *1)	-
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (b)	See data.	Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (a)		N/A	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)		Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.8	FCC: Section15.247(a)(1) IC: RSS-210 A8.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.9 RSS-Gen 4.10	FCC: Section15.247(d) IC: RSS-210 A8.5 RSS-Gen 7.2.1 and 7.2.3	[Tx] 2.1dB (with Video Camera) 4960.000MHz, AV, Horizontal [Rx] 3.6dB (with Video Camera) 1628.339MHz, AV, Vertical	Complied	Conducted/ Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

\*1) The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.

\* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

### **FCC 15.31 (e)**

The test was performed with the New Battery since the EUT is a battery-operated device, and the stable voltage (DC 3.3V) was supplied to the RF part of the EUT. Therefore, the EUT complies with the requirement.

### **FCC Part 15.203 Antenna requirement**

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

### **3.3 Addition to standard**

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	N/A	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

### **3.4 Uncertainty**

#### **EMI**

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	2.9dB	4.8dB	5.0dB	3.9dB	4.3dB	4.5dB	4.3dB
No.2	3.5dB	4.8dB	5.1dB	4.0dB	4.2dB	4.4dB	4.2dB
No.3	3.8dB	4.6dB	4.7dB	4.0dB	4.2dB	4.5dB	4.2dB
No.4	3.5dB	4.4dB	4.9dB	4.0dB	4.2dB	4.6dB	4.2dB

\*3m/1m/0.5m = Measurement distance

Power meter (+dB)	
Below 1GHz	Above 1GHz
1.0dB	1.0dB

Antenna terminal conducted emission and Power density (+dB)			Antenna terminal conducted emission (+dB)		Channel power (+dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

#### **Radiated emission test(3m)**

[Radiated Spurious Emission Tx] The data listed in this report meets the limits unless the uncertainty is taken into consideration.

[Radiated Spurious Emission Rx] The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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### 3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

\* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

### 3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

## **SECTION 4: Operation of E.U.T. during testing**

### **4.1 Operating Mode(s)**

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9  
Receiving (Rx)  
Inquiry

Details of Operating Mode(s)

<b>Test Item</b>	<b>Mode</b>	<b>Tested frequency</b>
Spurious Emission (Conducted/Radiated)	Tx (Hopping off) DH5	2402MHz 2441MHz 2480MHz
	Rx	2441MHz
Carrier Frequency Separation	Tx (Hopping on) DH5 Inquiry	2402MHz 2441MHz 2480MHz
20dB Bandwidth	Tx (Hopping off) DH5 Inquiry	2402MHz 2441MHz 2480MHz
Number of Hopping Frequency	Tx (Hopping on) DH5 Inquiry	-
Dwell time	Tx (Hopping on) -DH1, DH3, DH5 Inquiry	-
Maximum Peak Output Power	Tx (Hopping off) DH5 Inquiry	2402MHz 2441MHz 2480MHz
Band Edge Compliance (Conducted)	Tx DH5 -Hopping on -Hopping off	2402MHz 2480MHz
99% Occupied Bandwidth	Tx DH5 -Hopping on -Hopping off	2402MHz 2441MHz 2480MHz
<p>*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)</p> <p>*EUT has the power settings by the software as follows;  Power settings: 10dBm (IntPA: 23)  Software: RF Test Tool for Bluetooth Class1 Device Version 1.3.0.0</p> <p>*This setting of software is the worst case.</p> <p>Any conditions under the normal use do not exceed the condition of setting.</p> <p>In addition, end users cannot change the settings of the output power of the product.</p>		

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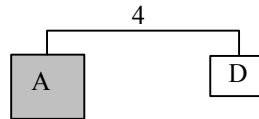
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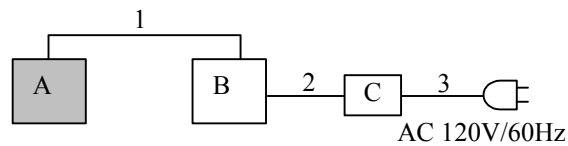
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## 4.2 Configuration and peripherals

### <With Earphone>



### <With Video Camera>



\* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

### Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Wireless Microphone	DV840210	4948	Canon Inc.	EUT
B	Video Camera	iVISHFS21	231020010641	Canon Inc.	-
C	AC Adapter	CA-570	ADBC2	Canon Inc.	-
D	Earphone	-	-	Canon Inc.	-

### List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	Signal Cable	0.2	Unshielded	Unshielded	-
2	DC Cable	1.6	Unshielded	Unshielded	-
3	AC Cable	1.5	Unshielded	Unshielded	-
4	Earphone Cable	1.0	Unshielded	Unshielded	-

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## **SECTION 5: Radiated Spurious Emission**

### **Test Procedure**

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

### **Test Antennas are used as below;**

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

**20dBc was applied to the frequency over the limit of FCC 15.209 / Table 2 of RSS-210 2.7 (IC) and outside the restricted band of FCC15.205 / Table 1 of RSS-210 2.7 (IC).**

Frequency	Below 1GHz	Above 1GHz		20dBc
Instrument used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz or RBW: 1MHz VBW: 270Hz *1)	RBW: 100kHz VBW: 300kHz (S/A)
Test Distance	3m	3m (below 10GHz), 1m*2) (above 10GHz)		3m (below 10GHz), 1m*2) (above 10GHz)

\*1) Used for the band edge of the carrier and the harmonics that can be measured. The VBW is based on the inverse of the duty cycle (see Appendix).

\*2) Distance Factor:  $20 \times \log(3.0\text{m}/1.0\text{m}) = 9.5\text{dB}$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

<b>Measurement range</b>	<b>: 30M-26.5GHz</b>
<b>Test data</b>	<b>: APPENDIX</b>
<b>Test result</b>	<b>: Pass</b>

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## **SECTION 6: Antenna Terminal Conducted Tests**

### **Test Procedure**

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3MHz or 5MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	1MHz	3MHz	As necessary capture the entire dwell time per hopping channel	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission	Less or equal to 5GHz (Range: 30MHz-25GHz)	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer

The test results and limit are rounded off to two decimals place, so some differences might be observed.

**Test data** : APPENDIX  
**Test result** : Pass